

## 20V N-Channel Enhancement Mode MOSFET

### Description

The AP2320MI uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 20V$   $I_D = 8A$

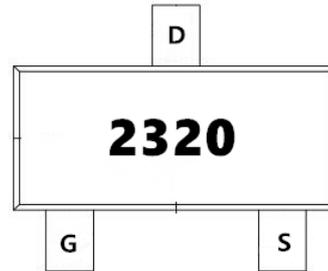
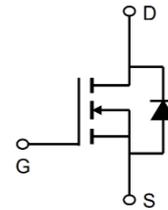
$R_{DS(ON)} < 12m\Omega$  @  $V_{GS}=4.5V$  (Type: 8.5m $\Omega$ )

### Application

3.3V MCU Drive

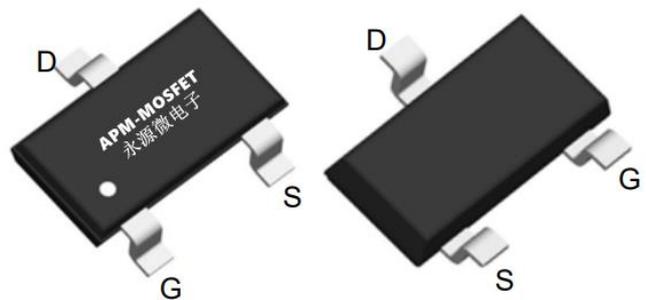
Load switch

Uninterruptible power supply



Top View

Bottom View



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP2320MI	SOT23-3L	2320	3000

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Max.	Units
$V_{DS}$	Drain-Source Voltage	20	V
$V_{GS}$	Gate-Source Voltage	$\pm 12$	V
$I_{D@TA=25^\circ\text{C}}$	Continuous Drain Current, $V_{GS} @ 4.5V$	8	A
$I_{D@TA=70^\circ\text{C}}$	Continuous Drain Current, $V_{GS} @ 4.5V$	4.5	A
$I_{DM}$	Pulsed Drain Current <small>note1</small>	24	A
$E_{AS}$	Single Pulsed Avalanche Energy <small>note2</small>	18	mJ
$PD@TA=25^\circ\text{C}$	Power Dissipation	12	W
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +175	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	125	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.8	$^\circ\text{C/W}$



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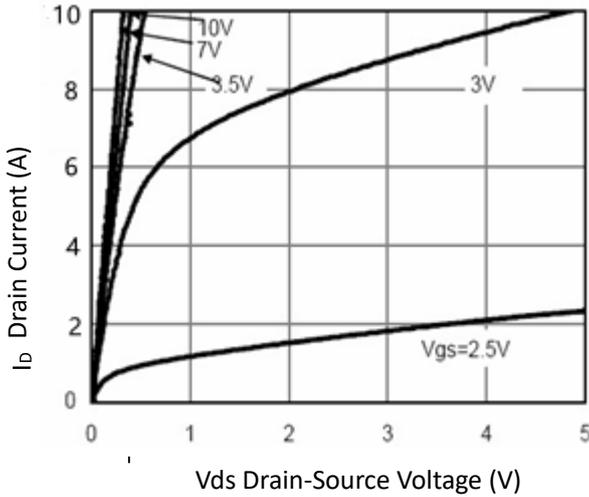
### Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	20	22	-	V
$IDSS$	Zero Gate Voltage Drain Current	$V_{DS}=20V, V_{GS}=0V$	-	-	1	$\mu A$
$IGSS$	Gate-Body Leakage Current	$V_{GS}=\pm 12V, V_{DS}=0V$	-	-	$\pm 100$	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	0.5	0.65	1.2	V
$R_{DS(ON)}$	Drain-Source On-State Resistance	$V_{GS}=4.5V, I_D=6A$	-	8.5	12	m $\Omega$
$R_{DS(ON)}$	Drain-Source On-State Resistance	$V_{GS}=2.5V, I_D=3A$	-	1.0	15	m $\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5V, I_D=20A$	10	-	-	S
$C_{iss}$	Input Capacitance	$V_{DS}=10V, V_{GS}=0V,$ $F=1.0MHz$		625		PF
$C_{oss}$	Output Capacitance			162		PF
$C_{rss}$	Reverse Transfer Capacitance			105		PF
$t_{d(on)}$	Turn-on Delay Time	$V_{GS}=10V, V_{DS}=10V$ $RL=0.5\Omega, R_{GEN}=3\Omega$	-	4.5	-	nS
$t_r$	Turn-on Rise Time		-	9.2	-	nS
$t_{d(off)}$	Turn-Off Delay Time		-	18.7	-	nS
$t_f$	Turn-Off Fall Time		-	3.3	-	nS
$Q_g$	Total Gate Charge	$V_{GS}=10V, V_{DS}=10V, I_D=20A$		15		nC
$Q_{gs}$	Gate-Source Charge			1.8		nC
$Q_{gd}$	Gate-Drain Charge			2.8		nC
$V_{SD}$	Diode Forward Voltage <sup>(Note 3)</sup>	$V_{GS}=0V, I_S=25A$	-	-	1.2	V
$I_S$	Diode Forward Current <sup>(Note 2)</sup>		-	-	25	A
$t_{rr}$	Reverse Recovery Time	$T_J = 25^{\circ}\text{C}, IF = 20A$ di/dt = 100A/ $\mu s$	-	18	-	nS
$Q_{rr}$	Reverse Recovery Charge		-	9.5	-	nC
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

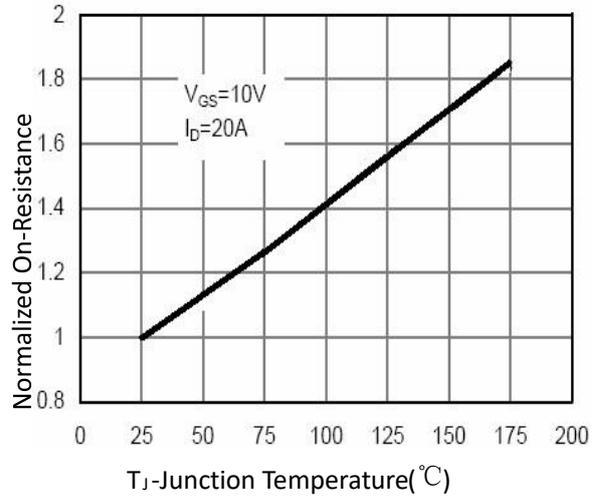
**Note :**

- 1、The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3、The power dissipation is limited by 150 $^{\circ}\text{C}$  junction temperature
- 4、The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

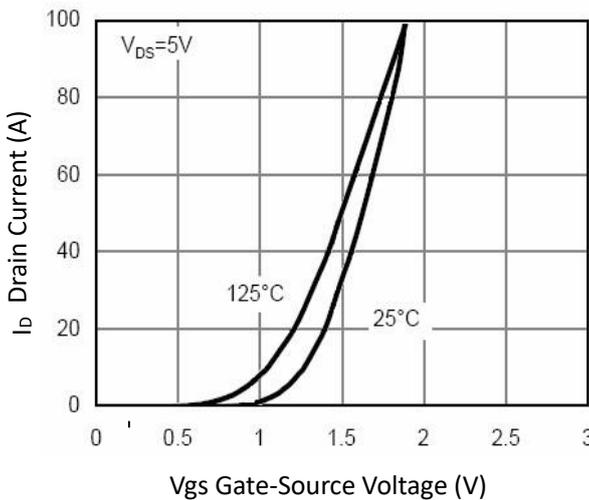
**Typical Characteristics**



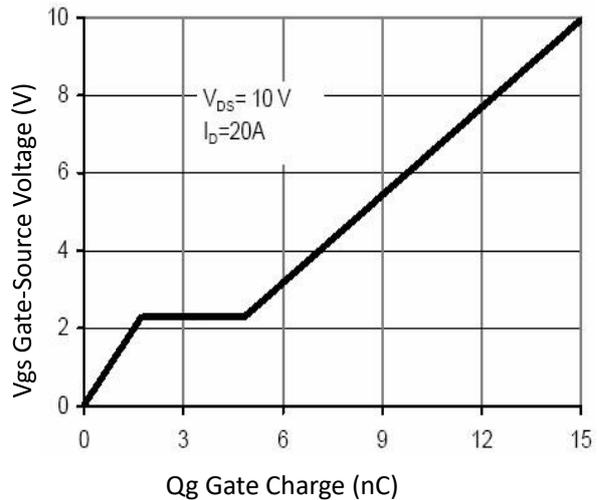
**Figure 1 Output Characteristics**



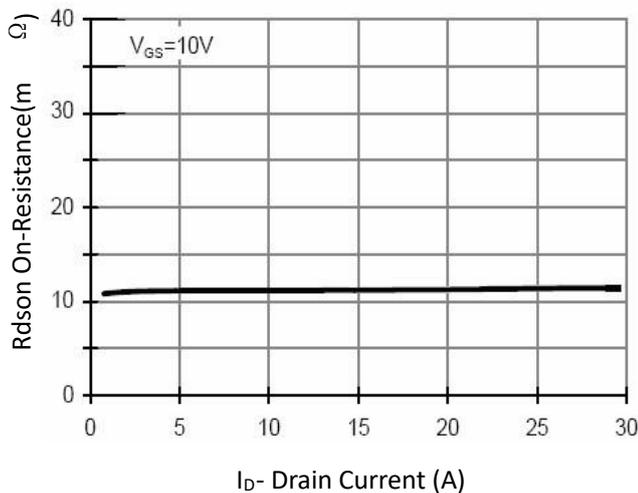
**Figure 4 Rdson-Junction Temperature**



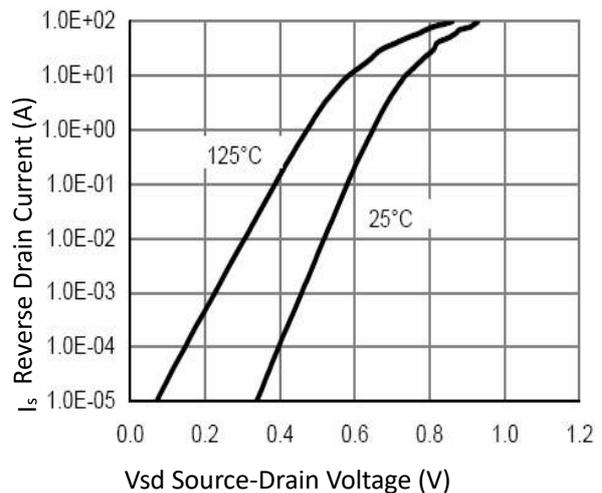
**Figure 2 Transfer Characteristics**



**Figure 5 Gate Charge**

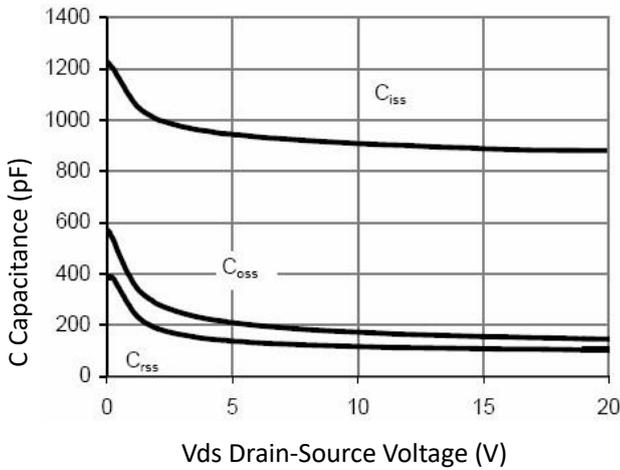


**Figure 3 Rdson- Drain Current**

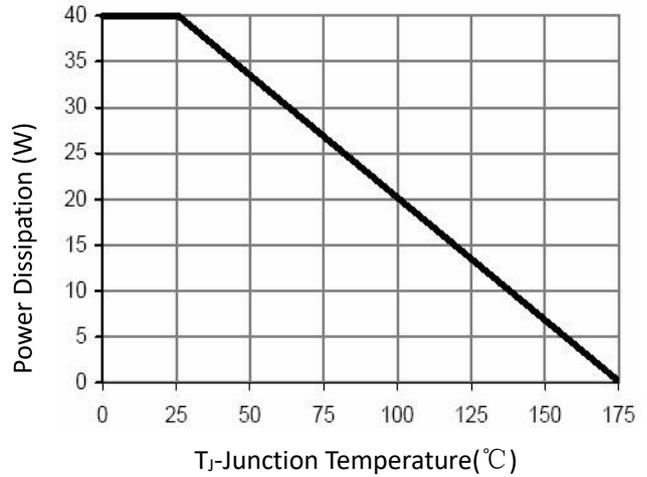


**Figure 6 Source- Drain Diode Forward**

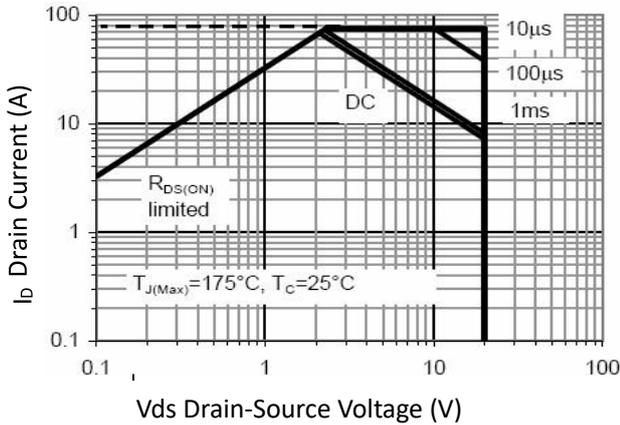




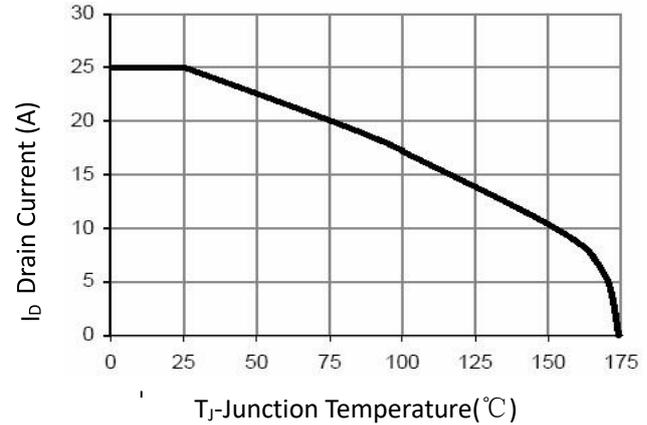
**Figure 7 Capacitance vs Vds**



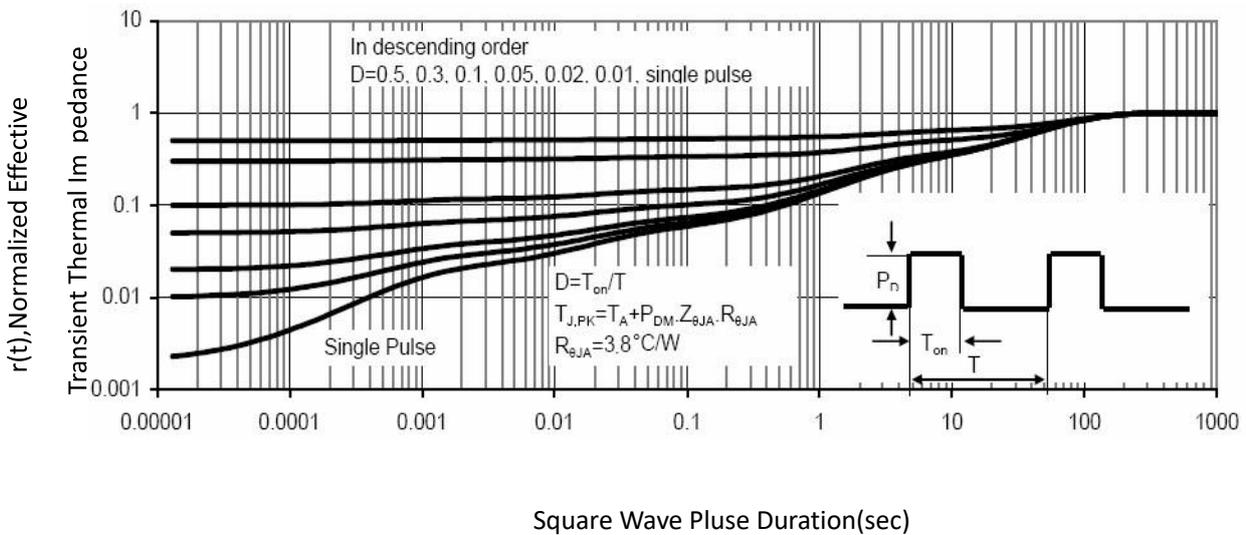
**Figure 9 Power De-rating**



**Figure 8 Safe Operation Area**

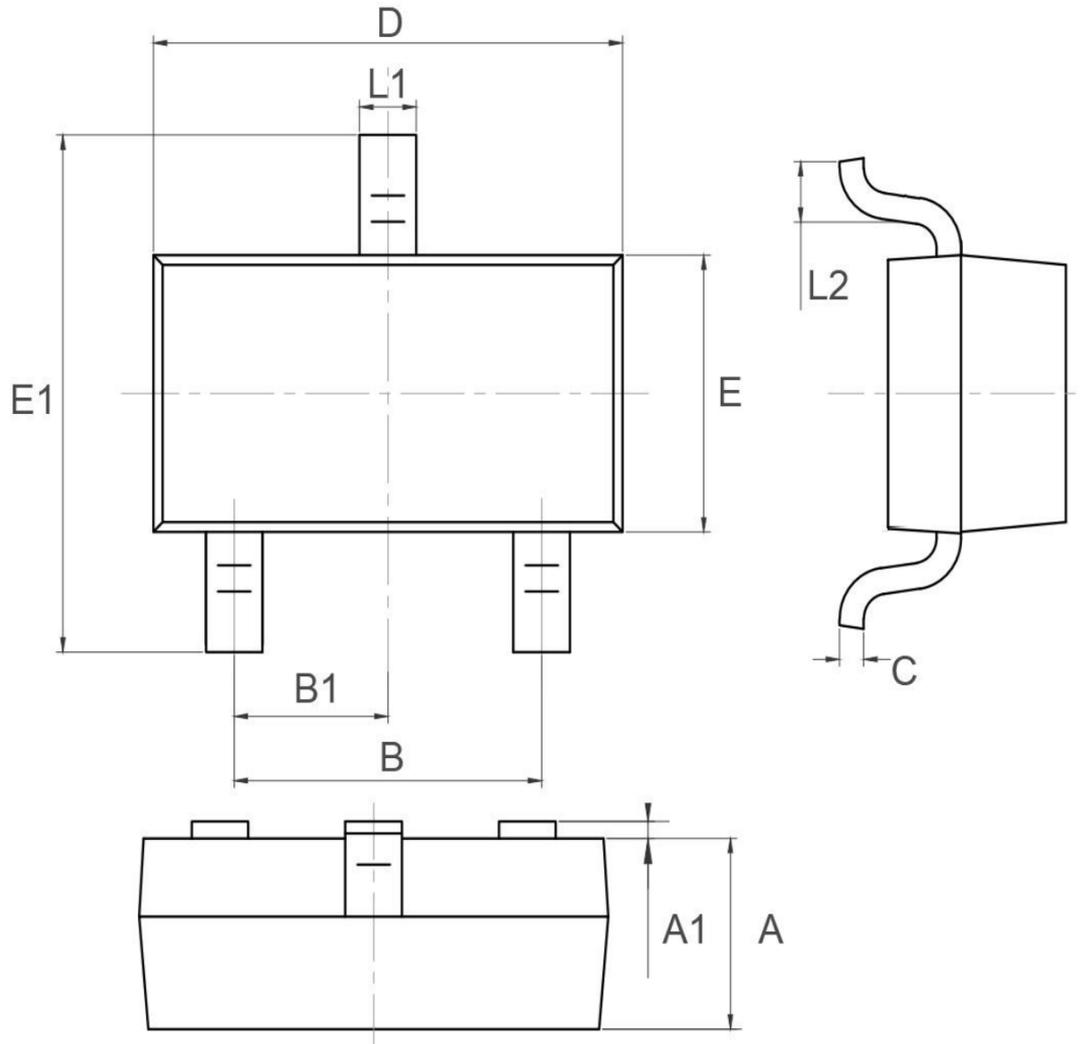


**Figure 10 Current De-rating**



**Figure 11 Normalized Maximum Transient Thermal Impedance**

### Package Mechanical Data-SOT23-3L-Single



Symbol	Dim in mm		
	min.	typ.	max.
A	1	1.1	1.2
A1	0	0.05	0.1
B	1.8	1.9	2
B1	0.95TYP		
C	0.1	0.15	0.2
D	2.82	2.92	3.02
E	1.5	1.6	1.7
E1	2.65	2.8	2.95
L1	0.3	0.4	0.5
L2	0.3	0.45	0.6

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<b>Edition</b>	<b>Date</b>	<b>Change</b>
Rve1.0	2019/9/31	Initial release
Rve1.1	2022/9/9	Change layout format
Rve1.2	2025/3/12	Update LOGO And Corrected Manual POD

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